

**Notice of References Cited**

Application/Control No.

09/559,691

Applicant(s)/Patent Under  
Reexamination  
LEE ET AL.

Examiner

Emmanuel Bayard

Art Unit

2631

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**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,802,174	01-1989	Hiraiwa et al.	714/789
	B	US-6,208,713	03-2001	Rahrer et al.	379/67.1
	C	US-5,859,861	01-1999	Oh, Dae-II	714/795
	D	US-5,349,608	09-1994	Graham et al.	375/341
	E	US-5,724,394	03-1998	Ikeda et al.	375/341
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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